EEBM 6381 - Advanced Concepts in Microscopy

EEBM 6381 (BMEN 6381) Advanced Concepts in Microscopy (3 semester credit hours) Continuation of EEBM 6380, with emphasis on advanced approaches such as vectorial diffraction, stochastic aspects of image formation and analysis. Prerequisite: BMEN 6380 or EEBM 6380 or instructor consent required. (3-0) R